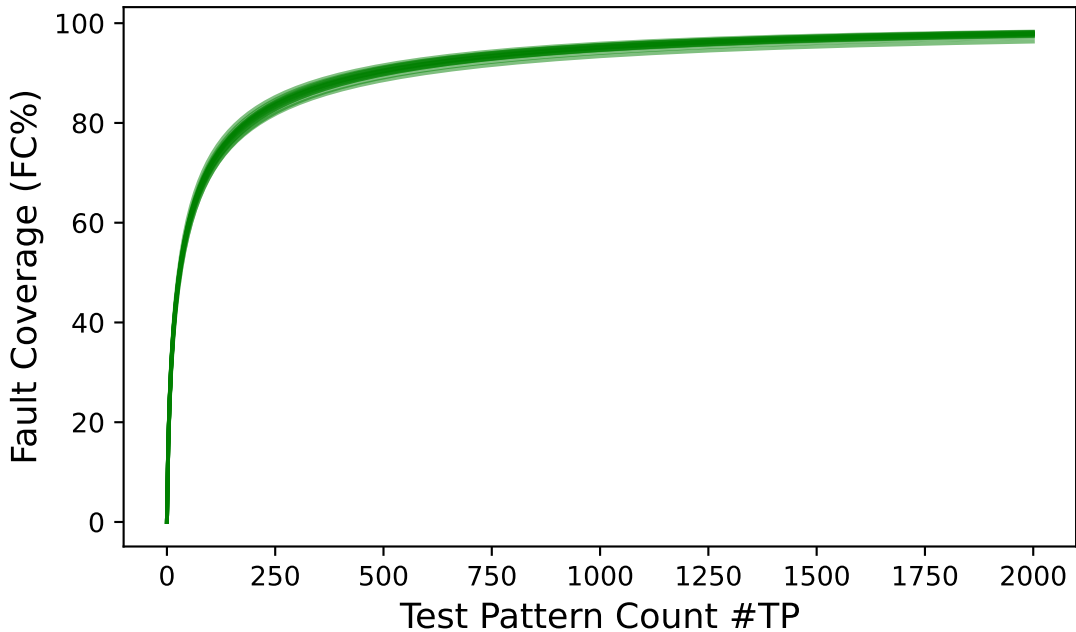


Dependency of fault coverage on random test patterns
for circuit int2float_synV1



The experiment is carried out 15 times.